Se	aı	rch	No	te	S	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/797,082	ONISHI ET AL.	
Examiner	Art Unit	
Rodney H. Bonck	3681	

	SEAR	CHED	
Class	Subclass	Date	Examiner
192	87.11		
	87.14		,
	87.15		
	113.34		
	70.12		
	70.2		
475	146		
	280		
	316		
	322		
	328	06/15/05	BUB
		/ /	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
-			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST BRS Search (enclosed)	04/15/05	RUB	
	,		